

**UNITED STATES PATENT AND TRADEMARK OFFICE**

Inventors:	Heinen	Group Art Unit:	2857
Application No.:	10/557,104	Examiner:	Charioui, M.
Filed:	27 November 2006	Confirmation No.:	5365
Subject:	INTEGRATED CIRCUIT WITH BIT ERROR TEST CAPABILITY		
Atty Docket No.:	20031035-02		

**PRELIMINARY AMENDMENT UNDER 37 CFR 1.114 (continued examination)**

COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Claims 1-12 were presented for examination. In a Final Action mailed May 14, 2008, all claims were rejected.

In response to the Final Action, Applicants hereby submit a preliminary amendment and request for continued examination.

A **Claims** listing begins on page 2.

**Remarks** begin on page 6.